

<b>Notice of References Cited</b>		Application/Control No. 10/591,289	Applicant(s)/Patent Under Reexamination HAGER ET AL.	
		Examiner JAMES W. TAYLOR II	Art Unit 4171	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2006/0281846 A1	12-2006	Hager et al.	524/430
*	B US-3,316,205	04-1967	DIEN CHI K	524/99
*	C US-5,445,871	08-1995	Murase et al.	428/215
*	D US-4,177,099	12-1979	Radzwill, John	156/88
*	E US-5,629,404	05-1997	Smith et al.	528/196
*	F US-2004/0209031	10-2004	Kawase et al.	428/049
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Sigma Aldrich screenshot from website showing the price of nanoparticle indium tin oxide, taken 3/28/2008.
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.